

Search Notes

Application/Control No.

10/617,817

Examiner

Roberto Velez

Applicant(s)/Patent under
Reexamination

TERAISHI, TOSHIO

Art Unit

2829

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search: (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) PLUS Search and Text Search (See Search History)	11/28/2006	RV